

**Search Notes**

Application/Control No.

10/791,725

Examiner

Mohamed Charioui

Applicant(s)/Patent under  
Reexamination

MARUYAMA, DAISUKE

Art Unit

2857

**SEARCHED**

Class	Subclass	Date	Examiner
702	57-59, 64, 108, 117, 118	6/16/2005	MC
702	119, 120	6/16/2005	MC
702	124, 126	6/16/2005	MC
702	185, 189	6/16/2005	MC
714	30, 718	6/17/2005	MC
714	724, 725	6/17/2005	MC
714	741	6/17/2005	MC
324	76.11	6/17/2005	MC
324	534	6/17/2005	MC
327	203	6/17/2005	MC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted with Hal Wachsman	6/16/2005	MC
East: (test near pattern) and ((failure or defect or fault or malfunction) with delay) and (flip\$flop or "FF")	6/16/2005	MC
East: (test near pattern) and ((failure or defect or fault or malfunction) with delay) and (gate with (test near pattern))	6/16/2005	MC
East: (test near pattern) and ((failure or defect or fault or malfunction) with delay) and "don't care"	6/17/2005	MC
East: automatic\$6 wit test\$3 with pattern and (delay near failure)	6/17/2005	MC